

## Supplementary Information

### Detection and Quantification of Trace Technetium in the Presence of Molybdenum Using Laser-Induced Breakdown Spectroscopy

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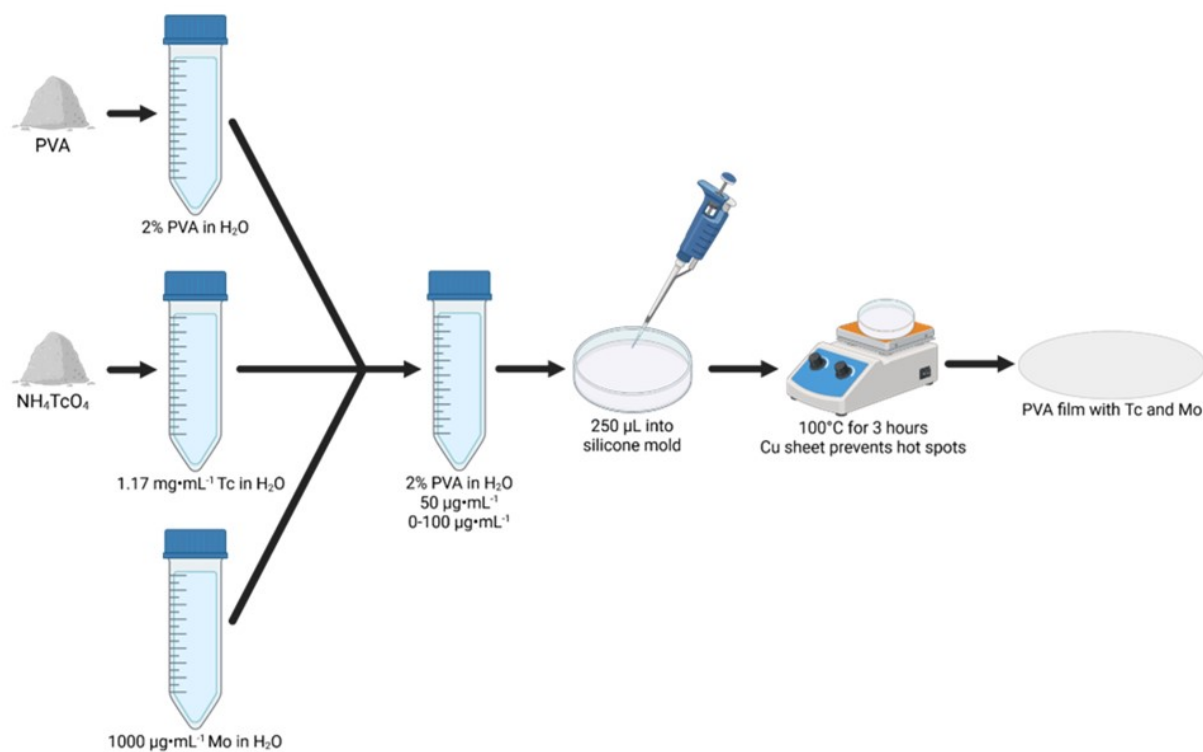
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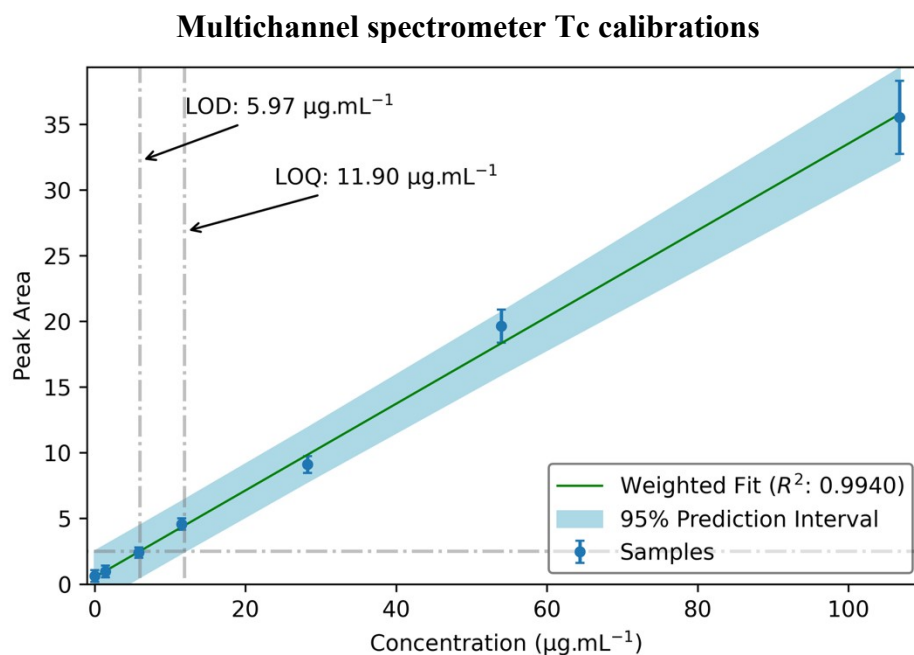
#### Summary of contents:

- Sample preparation schematic
- Multichannel univariate calibration curves
- CZ ICCD univariate calibration curves
- Survey of Tc emissions at trace concentrations in Mo matrix
- Survey of concentrated Tc emissions on Si substrate

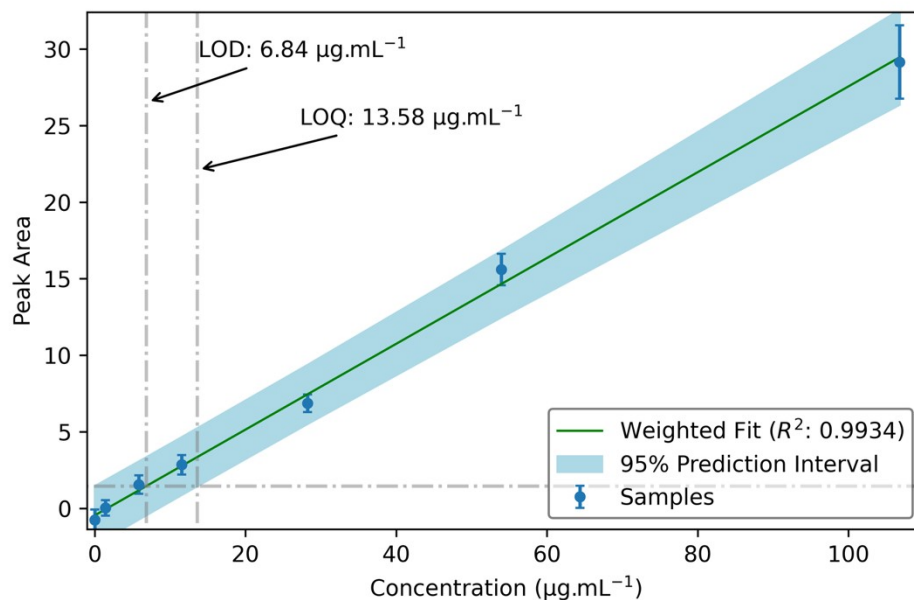
## Sample Preparation and PVA Conversion



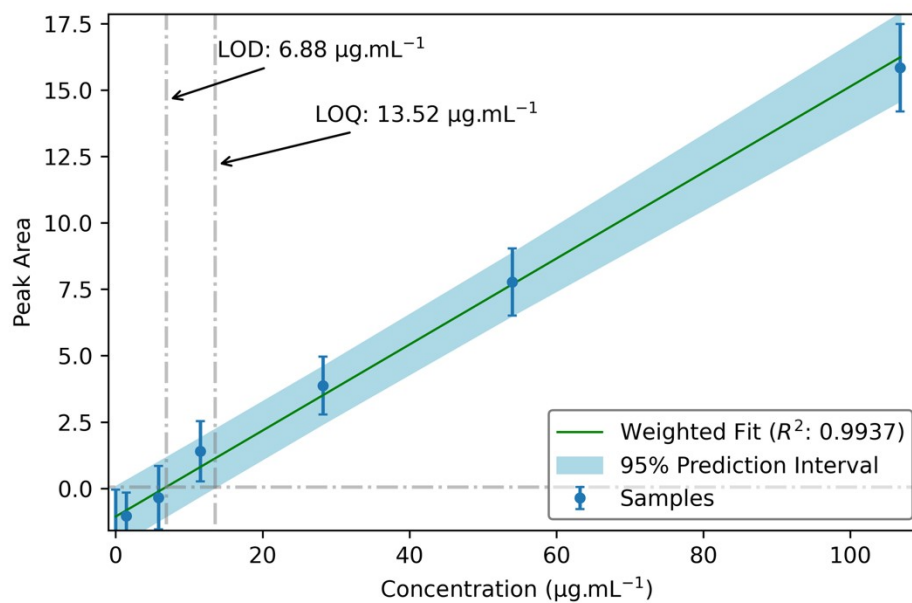
**Figure S1.** Diagram of the aqueous sample preparation and subsequent PVA film conversion.



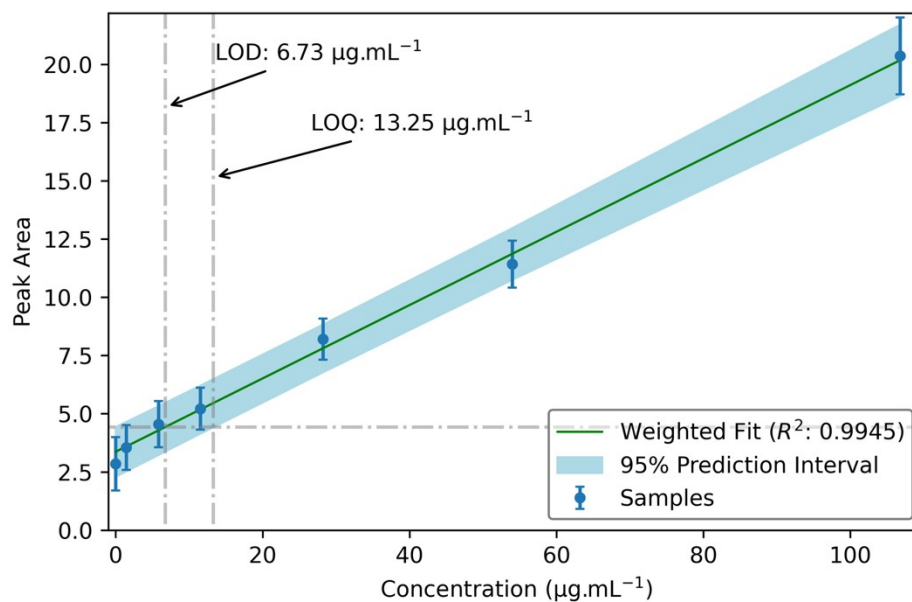
**Figure S2.** Tc calibration curve based on the 254.32 nm emission peak using the multichannel spectrometer.



**Figure S3.** Tc calibration curve based on the 260.99 nm emission peak using the multichannel spectrometer.

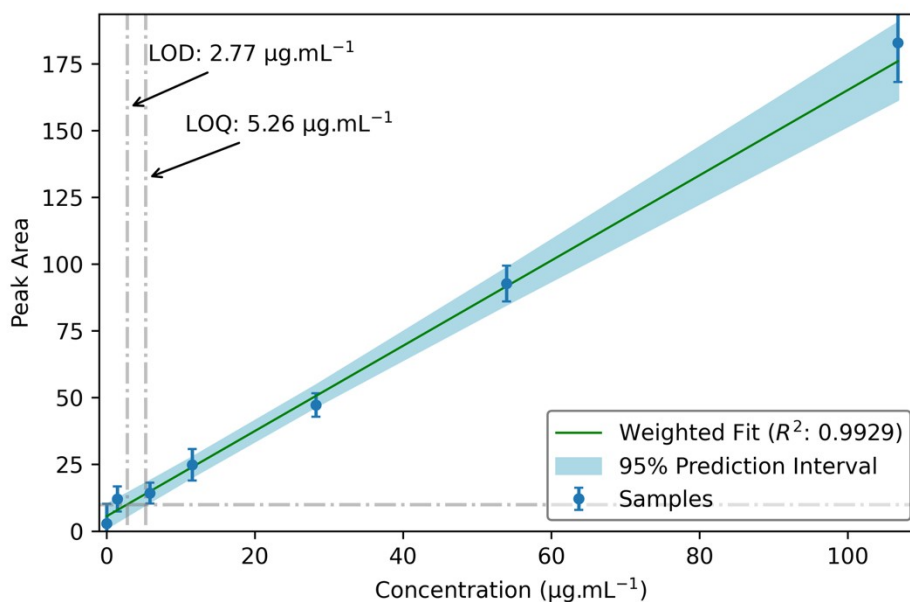


**Figure S4.** Tc calibration curve based on the 363.61 nm emission peak using the multichannel spectrometer.

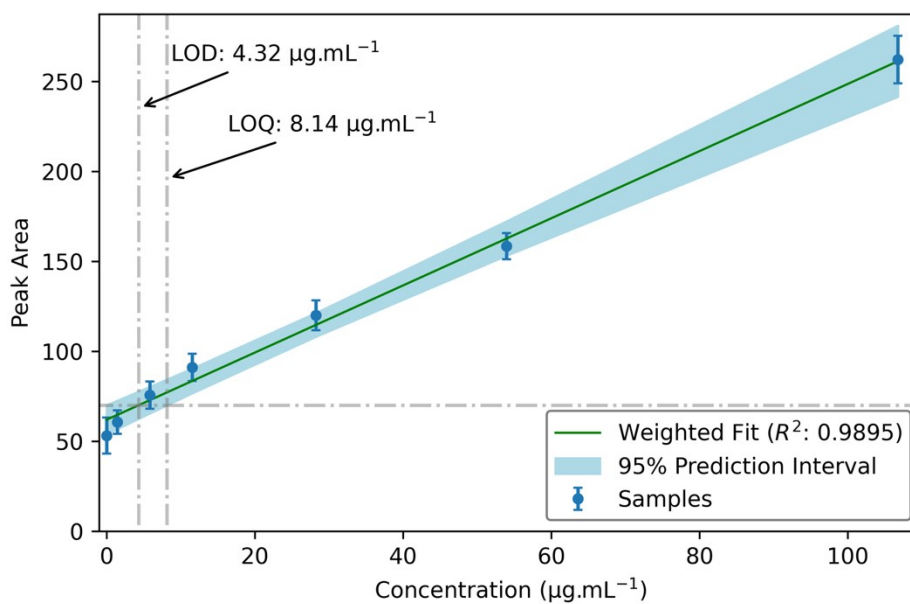


**Figure S5.** Tc calibration curve based on the 403.16 nm emission peak using the multichannel spectrometer.

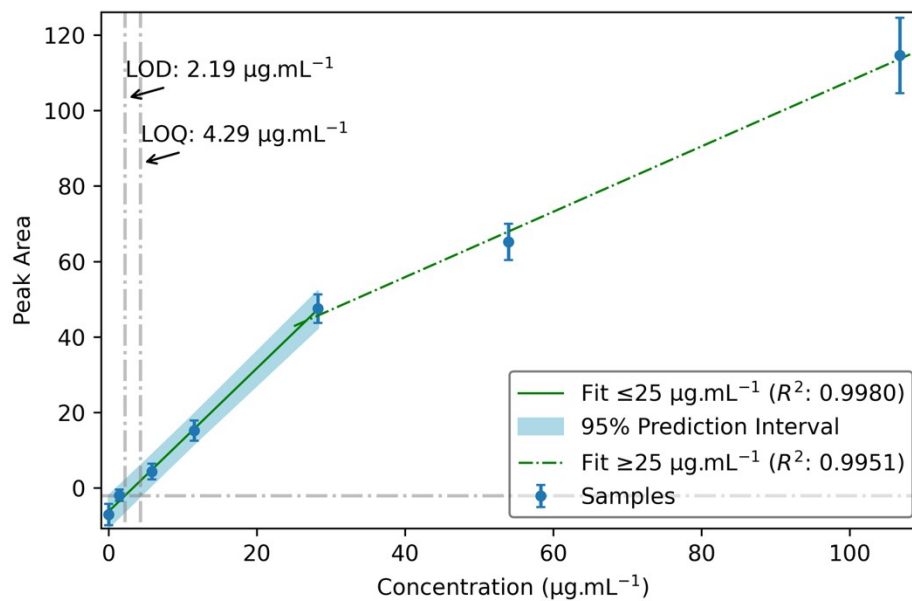
### CZ ICCD spectrometer Tc calibrations



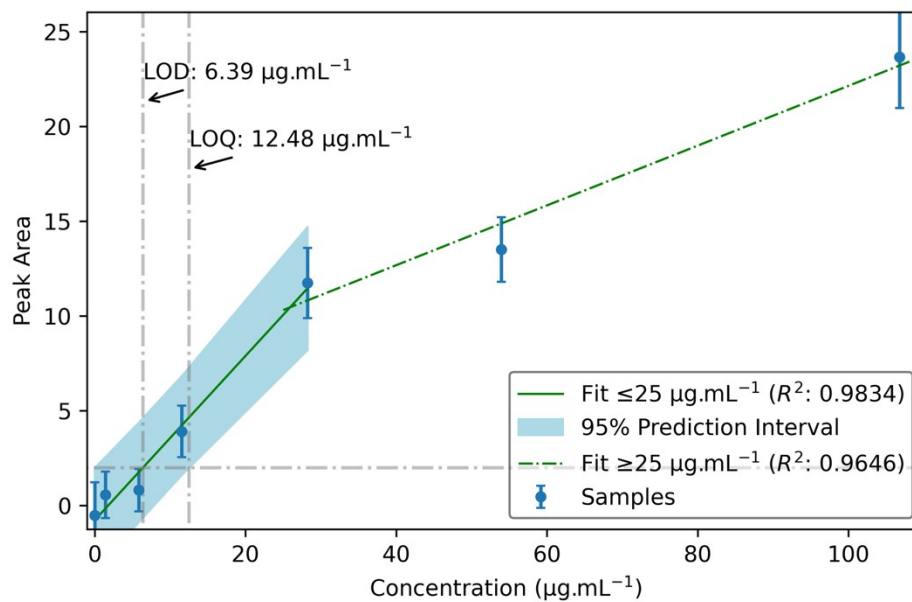
**Figure S6.** Tc calibration curve based on the 398.49 nm emission peak using the CZ ICCD spectrometer.



**Figure S7.** Tc calibration curve based on the 404.91 nm emission peak using the CZ ICCD spectrometer.

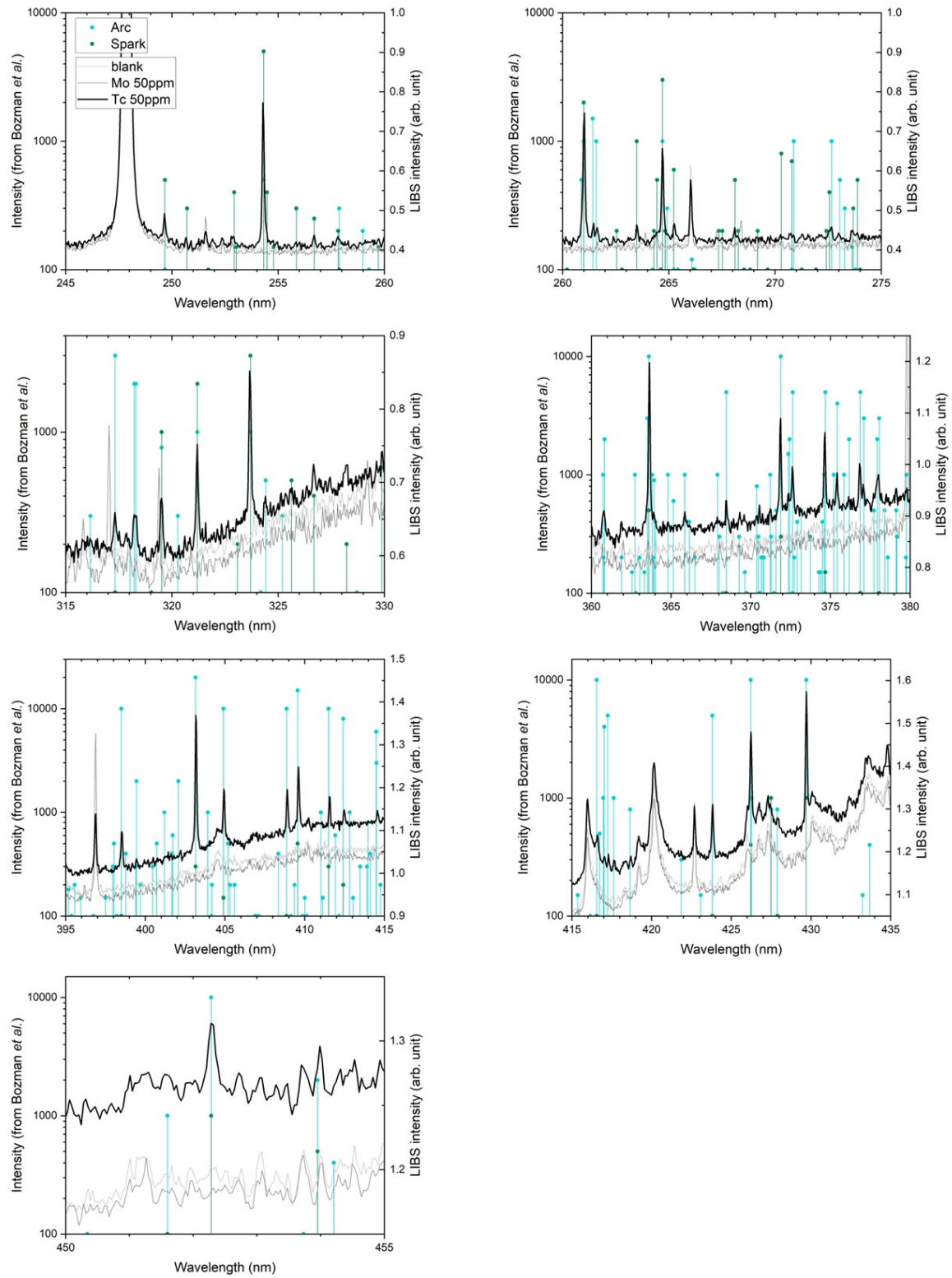


**Figure S8.** Tc calibration curve based on the 321.20 nm emission peak using the CZ ICCD spectrometer.



**Figure S9.** Tc calibration curve based on the 328.20 nm emission peak using the CZ ICCD spectrometer.

## Survey of Tc emissions at trace concentrations in Mo matrix





## Survey of concentrated Tc emissions on Si substrate

